

OIP 6 APR 16 2004 U.S. PATENT & TRADEMARK OFFICE		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.140DV1C1	APPLICATION NO. 10/757,638
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT Li et al.		
(USE SEVERAL SHEETS IF NECESSARY)		FILING DATE January 13,2004	GROUP Unknown	2824

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
MFZ	1	6,475,854	11/2002	Narwankar et al.			
MFZ	2	6,403,414	06/2002	Marsh			
MFZ	3	6,271,131	08/2001	Uhlenbrock et al.			
MFZ	4	6,201,271	03/2001	Okutoh et al.			
MFZ	5	6,180,974	01/2001	Okutoh et al.			
MFZ	6	6,140,230	10/2000	Li			
MFZ	7	5,902,651	05/1999	Westmoreland et al.			
MFZ	8	5,783,716	07/1998	Baum et al.			
MFZ	9	5,763,007	06/1998	Weillier			
MFZ	10	5,672,385	09/1997	Jimba et al.			
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MFZ	12	5,552,327	09/1996	Bachmann et al.			
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MFZ	14	US 2001/0000865 A1	05/2001	Gaughen et al.			
MFZ	15	US 2001/0043453 A1	11/2001	Narwankar et al.			
MFZ	16	US 2001/0044207 A1	11/2001	Marsh			
MFZ	17	US 2002/0076492 A1	06/2002	Loan et al.			

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
MFZ	18	Irving, Optical Diagnostics for Thin Film Processing, Academic Press, 1996, page 29.
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EXAMINER	DATE CONSIDERED
<i>Mark J. Hunter</i>	7/19/04

\*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.